

Extension of the e-Long Slab

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A red handwritten signature, likely of the speaker or organizer.

CALICE Meeting
"everywhere"
28/09/2020

1st 'electric long slab' (2018)

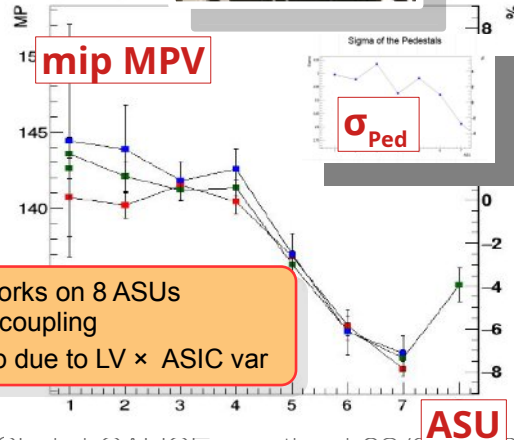
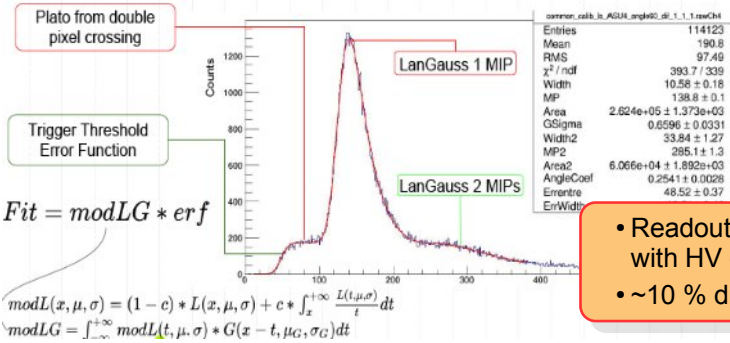


Support of interface boards + 12 ASUs (DBD)

- 2+6+4 ASUs = ~3.2 m
- Rotatably along long axis (for beam test)
- Rigidity : $\leq \sim 1$ mm per ASU
- Total access to upper and lower parts
 - 320 μ m Baby wafers (4x4 pixels) on the bottom



Fit with Mod LanGau function



- Readout works on 8 ASUs with HV decoupling
- ~10 % drop due to LV \times ASIC var

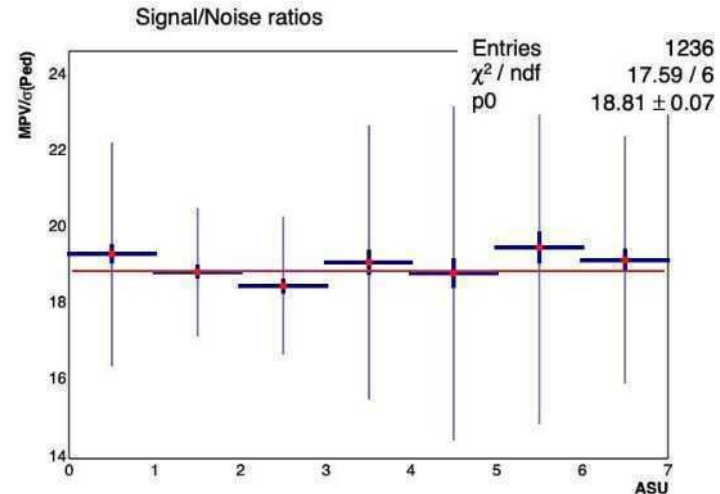
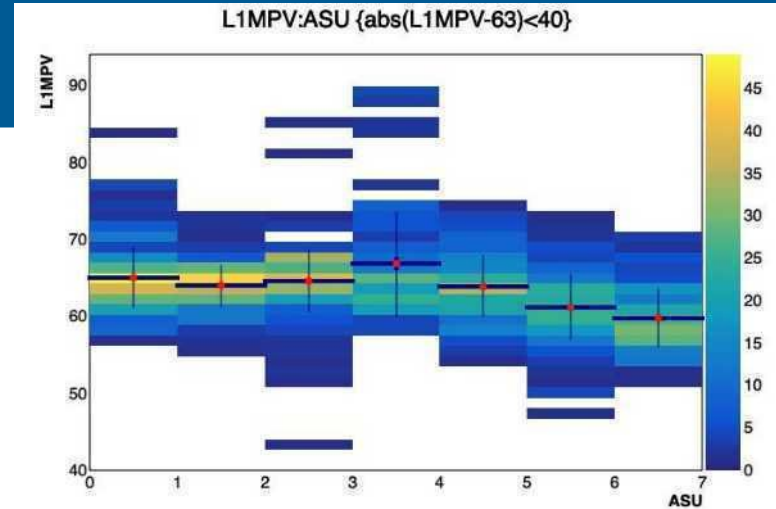


Signal over Noise ratios

The signal-to-noise ratio is defined as the most-probable-value (mpv) of a mip* divided by the pedestal width.

- in highly granular (self-triggering) calorimeters, a noise cut above 5–6 σ is mandatory, while a cut at $\frac{1}{2}$ mip will ensure a good efficiency, resulting in $S/N > 10-12$.
- A constant $S/N \sim 19$ is observed in the readout branch unaffected by the variations of the gain along the slab.

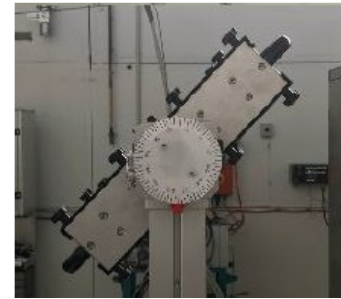
mip* = [punch-through electron]



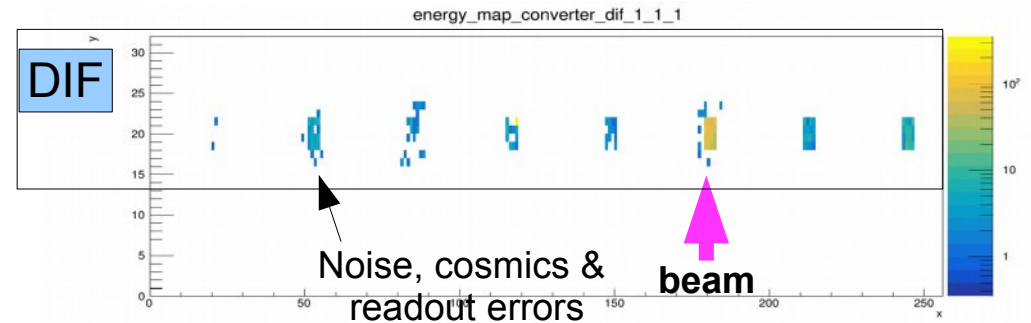
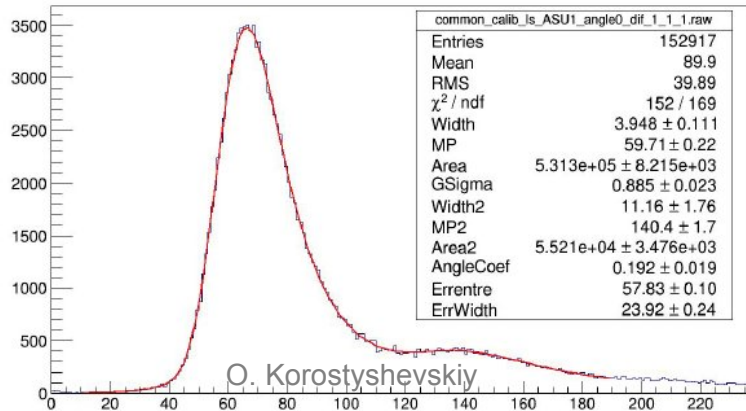
DESY-2018 beam test

2 weeks beg of July: full test of all prototypes:

- Electric long slab: **8 FEV11** + baby-wafers
- Very clean response to “mip” (punch through e^-)
- 1/2h beam on each ASU @ 0, 45, 60°



common_calib_ls_ASU1_angle0_dif_1_1_1.raw



Electronics adjustments

Path length induced reflexions on clock line

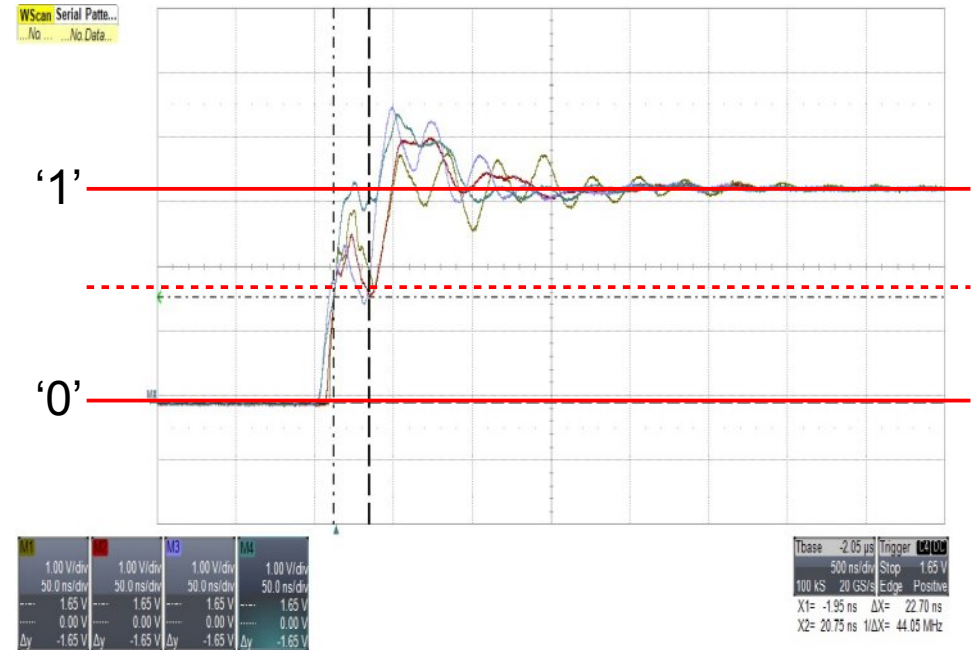
- Fluctuation over logical level
- Extra clock tick → bad ASIC configuration
- RC filter adaptation (Sigrity simulation)

Impedance adaptation required depending on length

- Limited to 8 FEV12 + baby-wafers

Noise in the signal

- High frequency perturbation in the HV line
- Solved by RC filters on the HV line
- Possible back-propagation of ASICs noisy channel through HV ?



Also issues on the data routing...

ASU: 11 years of R&D



Most complex element: electro-mechanical integration

- Distrib / Collect signals from VFE (ASICs), Analog & Digital with dyn. range ≥ 7500
- Mechanical placer & holder for Wafers \rightarrow precision
- Thickness constraints

FEV11

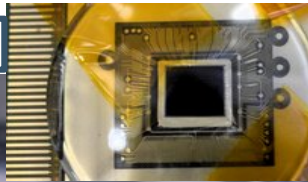
DIF + SMB

ASU

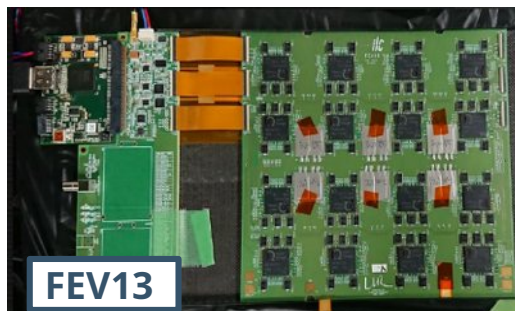
equipped with 4 Si-wafers

256 P-I-N diodes
0.25 cm² each
9 x 9 cm² total area

FEV11-COB



FEV13

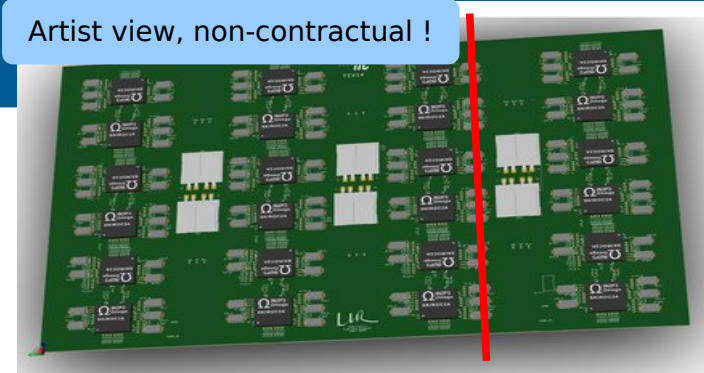


Milestone	Date	Object	Details	REM
1 st ASIC proto	2007	SK1 on FEV4	36 ch, 5 SCA	proto, lim @ 2000 mips
1 st ASIC	2009	SK2	64ch, 15 SCA	3000 mips
1 st prototype of a PCB	2010	FEV7	8 SK2	COB
1 st working PCB	2011	FEV8	16 SK2 (1024 ch)	CIP (QGFP)
1 st working ASU in BT	2012	FEV8	4 SK2 readout (256ch)	best S/N ~ 14 (HG), no PP retriggers 50–75%
1 st run in PP	2013	FEV8-CIP		BGA, PP
1 st full ASU	2015	FEV10	4 units on test board 1024 channel	S/N ~ 17–18 (High Gain) retrigger ~ 50%
1 st SLABs	2016	FEV11	7 units	
pre-calo	2017	FEV 11	7 units	S/N ~ 20 (12) _{Trig} , 6–8 % masked
1 st technological ECAL	2018	SLABvFEV11 & FEV13 SK2a+ Compact stack Long Slab	SK2 & SK2a (\rightarrow timing) 8 ASUs	Improved S/N Timing...
1 st working COB	2019	FEV-COB	2x1/4 ASUs	

Potential FEV14 (2021?)

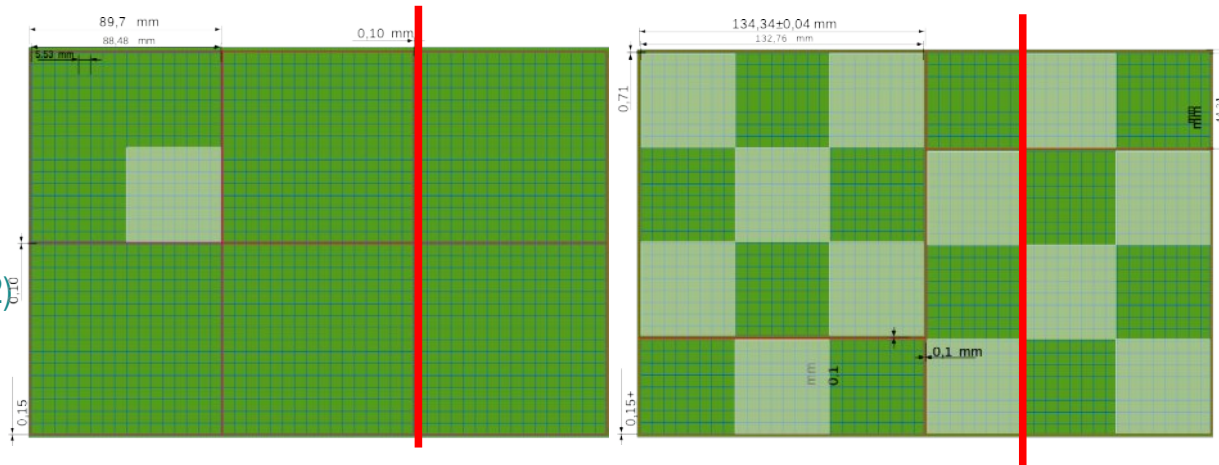
FEV13b? 2

HPK « No 8" wafer bef. end 2021 »



FEV14: Design PCB just started

- Compatible ~~8" et 6" wafers~~ ; ~~dimensions x1.5 (18x27 cm?)~~
 - 6 Matrices 6" OR 2 x 1,5 Matrices 8"
- ~~24 ASICs vs 16 ASICs~~
 - Less cards ⇒ Less connections
- Improved scalability & maintenance
 - 1 HV per card ⇒ independent test, exchangeability
 - Bloc diagrams ⇔ Sharing BGA / COP ?
- LV Regulation on board with LDO ?
 - + monitoring ? T°, V, ID (⇔ DB)
- Corrected data & clock distributions
 - Must be OK for 2,1 m (EndCaps) = 8 FEV14 (12 FEV12)
 - Timing ≤ 0,1 ns ? → for SK3 ?
- Compatibility new DAQ (≠ FEV13)



A Long Slab with “FEV13b”

Adaptative design wrt FEV12

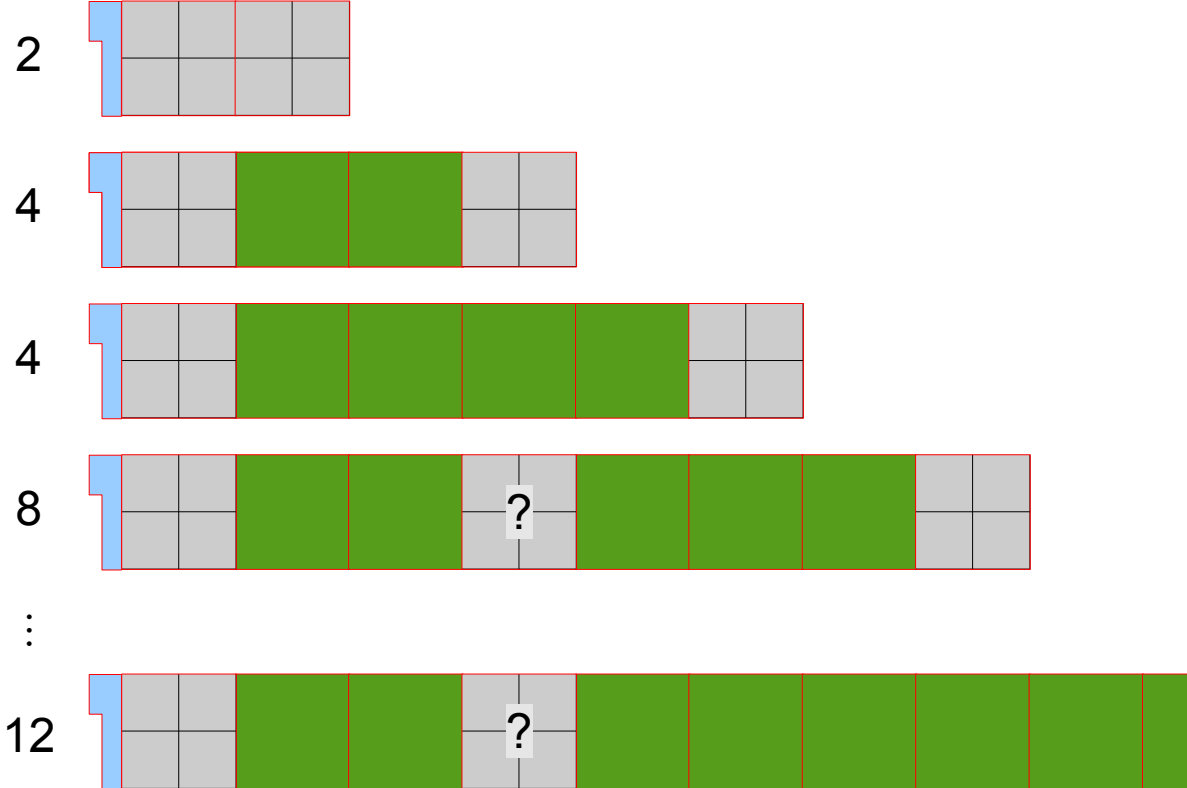
- Integration of new DAQ with Power Scheme
 - (see Jihane presentation)
- Possibility to include FEV13b-COBs in LS

Modular design :

- Incremental length

Full equipped ends of SLAB

- 1st and Last ASU
- Regulators / Decoupling on each ASU
 - Shower response at end of SLAB
- Possible integration new ASU's in stack



First steps (2020):

Test LDO's scheme in situation

- Several implementation on small insert mezzanine between ASU's
- Measure stability and behaviour in PP

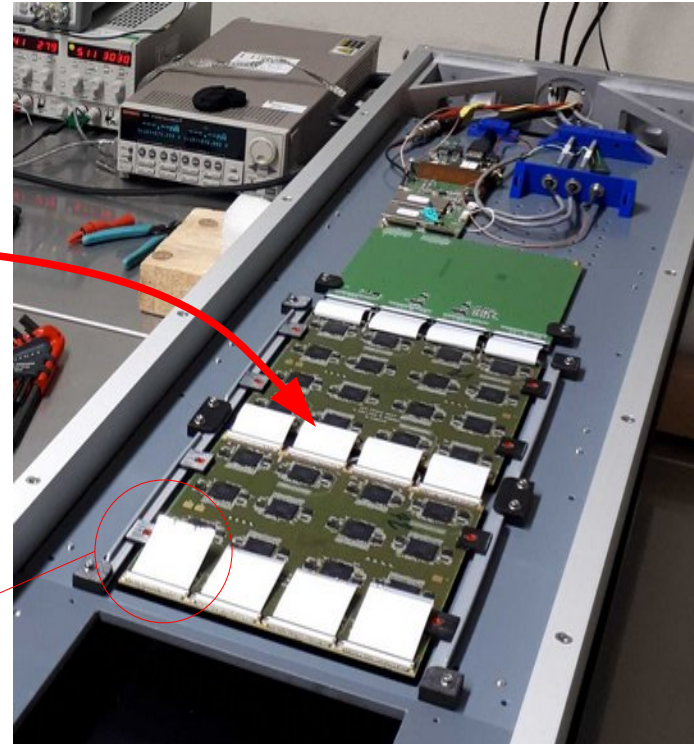
Implement the interface with SLBoard (v2)

- for Power Pulsing testing
 - remove / raise current limitations

Package additional SK2a's

- Test them

Compatible
with GradConn



Implication of HL schemes

Higher $\mathcal{L} \Rightarrow$

- Occupation / bunch train \nearrow
 - More memory for events
 - But large margins

Higher repetition rates \times longer bunch

- Power = $f_{\text{rep}} \times \sum P_{\text{ASIC_part}} \times \tau_{\text{spill_part}}$

- $\tau_{\text{spill}} = \tau_{\text{Ramp-up}} + \tau_{\text{Train}} + \tau_{\text{Conv}}$
 $= \mathcal{O}(\mu\text{s}) + \{ \dots \} + \mathcal{O}(100\text{'s } \mu\text{s})$
- $\tau_{\text{Train}} = \Delta T_{\text{bunches}} \times N_{\text{bunches}}$
- $\tau_{\text{Conv}} \propto (\text{occupancy} + \text{Noise} \geq \text{thr.})$

Critical also for Power budget

\Rightarrow Full ZERO suppr. needed

HL-ILC:

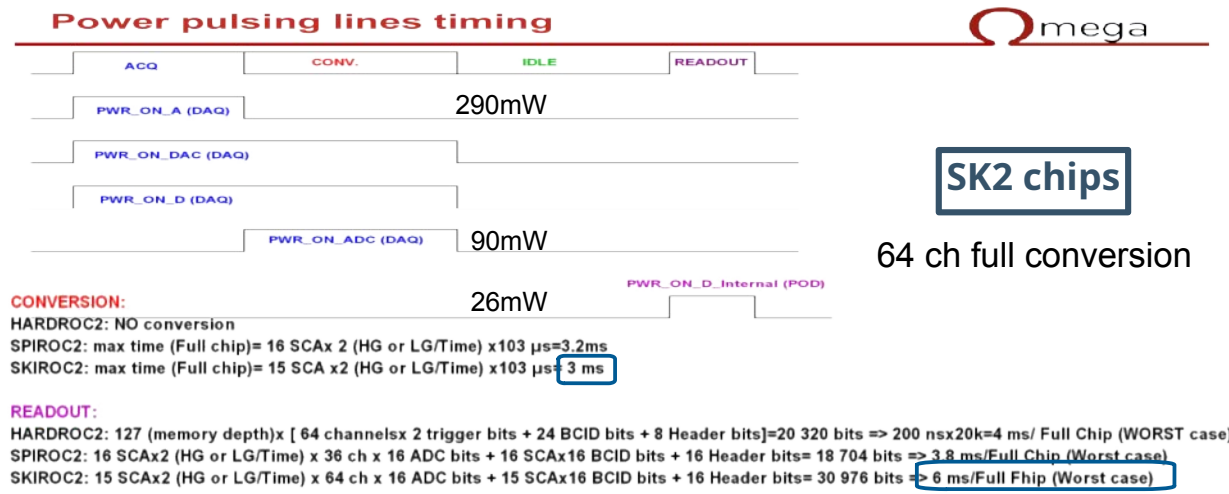
- $\mathcal{L} \times 4$ (6)
- $N_{\text{bunches}} \times 2 : \tau_{\text{Train}} : 1 \rightarrow 2 \text{ ms}$
- $f_{\text{rep}} \times 2$ (3): $5 \rightarrow 15 \text{ Hz}$

Dominated by ACQ time:
 $P(\sim 25\mu\text{W/ch}) \times 6$

HL-CLIC:

- $\mathcal{L} \times 2$
- $N_{\text{bunches}} \rightarrow : \tau_{\text{Train}} : 176 \text{ ns}$
- $f_{\text{rep}} \times 2 : 50 \rightarrow 100 \text{ Hz}$

Dominated by Set-up & Conversion time: $P(\sim 82\mu\text{W/ch}) \times 2$



Perspective: Just In Time ?

- Start of production of calorimeters in 2026 ?
- ↳ Preparation of production in 2025
- ↳ Pilote ECAL Module in 2024
- ↳ Pilote of SLABs in 2023
- ↳ 1st SLAB in 2022
- ↳ 1st ASU in 2021

⇐ achievable with LHC $\phi 2$?

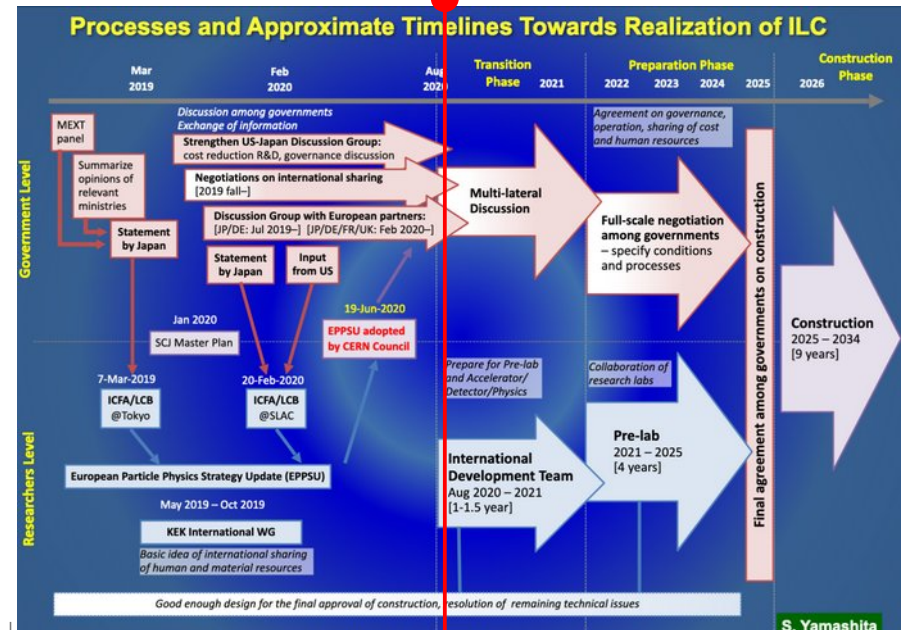
▷ all mechanical constraints We are standing here

Power & Thermal simulation to be reviewed

- HL scheme

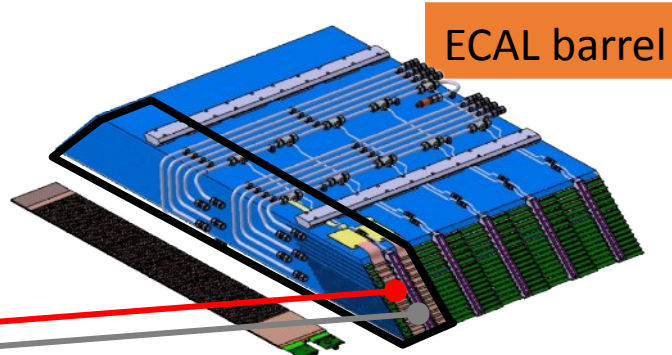
Final ASIC ≥ 2022

- Consumption & Timing

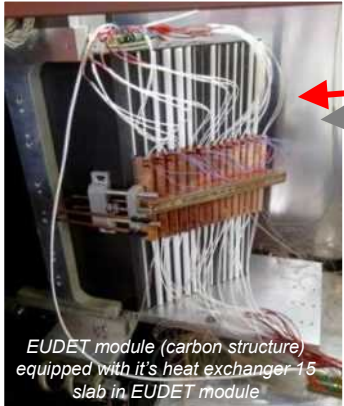


Back-up

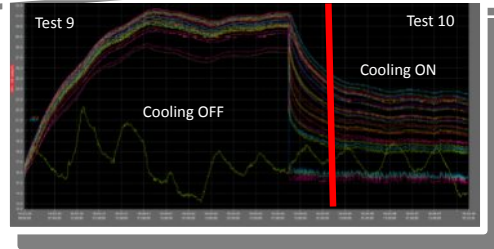
Passive cooling



ECAL barrel



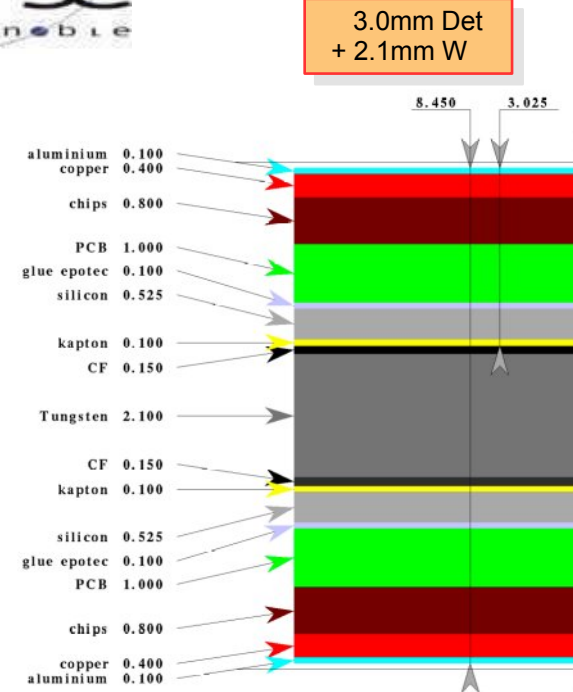
EUDET module (carbon structure) equipped with its heat exchanger 15 slab in EUDET module



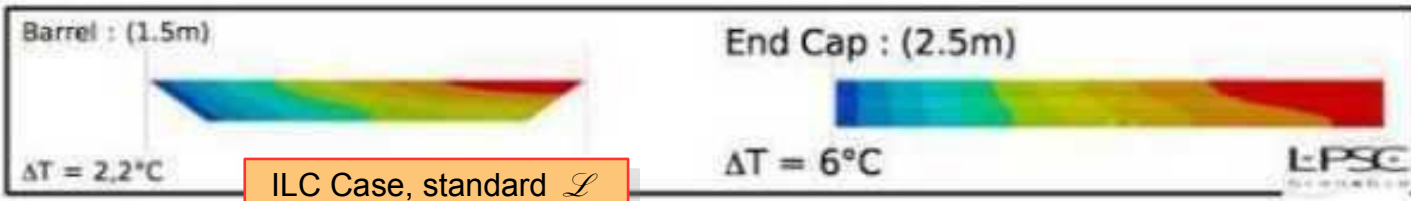
First tests results in line with simulations



ECAL end cap



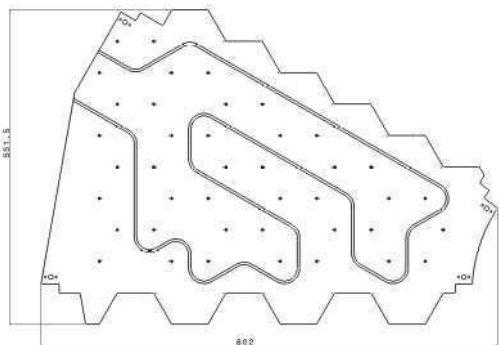
3.0mm Det + 2.1mm W



ILC Case, standard L

Active cooling → 'Continuous colliders'

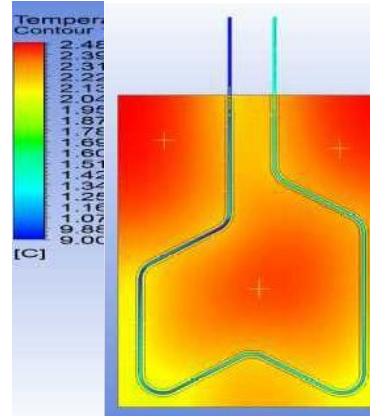
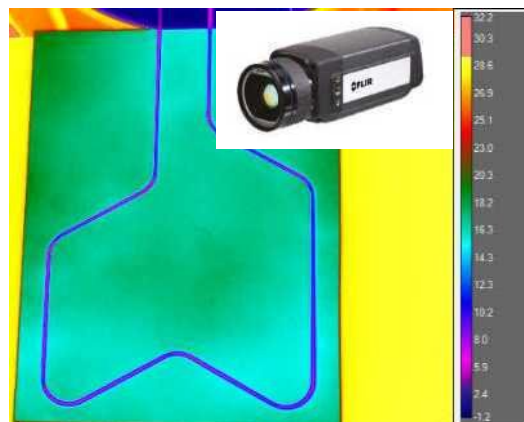
R&D using CMS studies (Courtesy of Th. Pierre-Emile from CMS-LLR group)



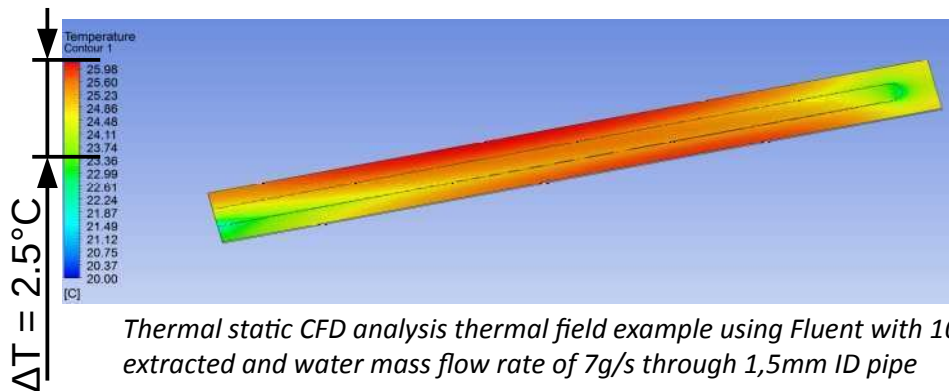
Copper plate prototype dimensions information



Pipe insertion on a cooling prototype for FEA correlation

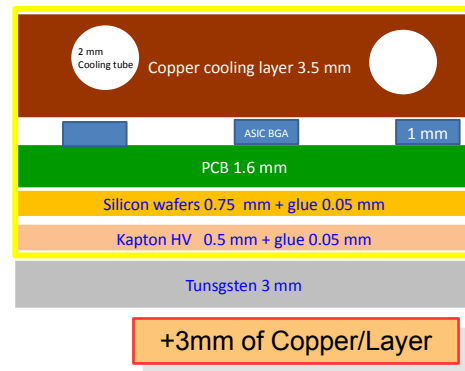


Pipe insertion on a cooling prototype



Thermal static CFD analysis thermal field example using Fluent with 100W extracted and water mass flow rate of 7g/s through 1,5mm ID pipe

- Pipe insertion process introduces some efficiency loss due to the thermal contact resistance.
- The benefit remains significant with regard to a passive cooling



= 2x cont. operation of a SLAB

MIP fluctuation

2 systematic effects has been identified

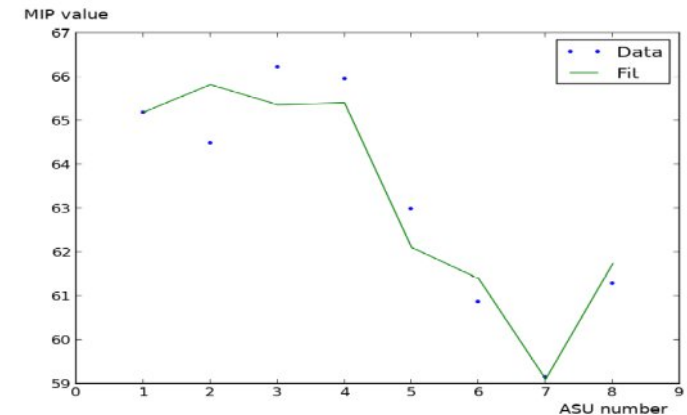
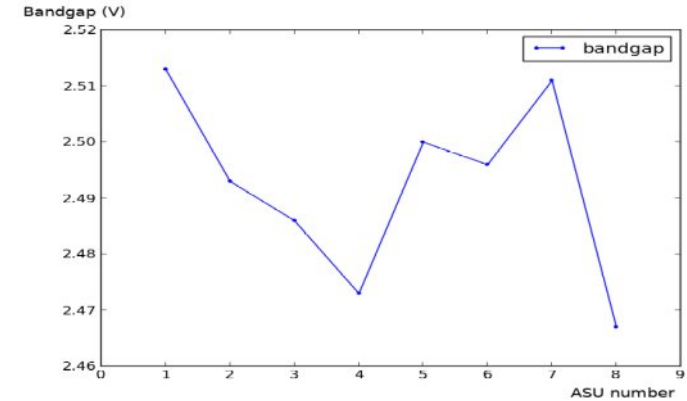
- Bandgap discrepancy (over 128 ASICs).
 - $\sigma=19.2$ mV peak to peak=200mV
- Voltage linear decrease over slab length

Curve shape can be fitted by weighted sum of these two effects

$$MIP(ASU) = a * ASU + b - c * \text{bandgap}(ASU)$$

Solutions

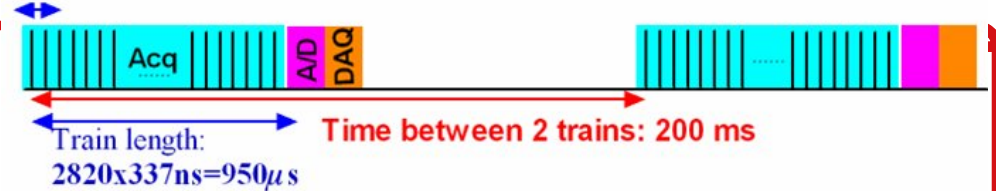
- Reduce bandgap in ASIC design (already reduced in Skiroc2a version)
- Compensate bandgap by software
- Select ASICs to mitigate fluctuation
- Use fixed length power supply to avoid discrepancy



POWER PULSING in SK2

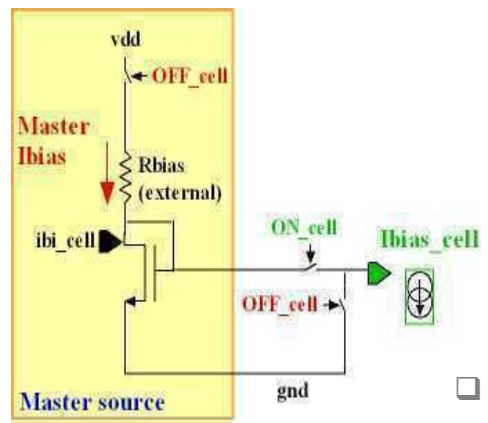
Time between 2 bunch crossings:

337 ns



Requirement:

- ❑ 25 $\mu\text{W}/\text{ch}$ with 0.5% duty cycle
- ❑ 500 μA for the entire chip



Power pulsing:

- ❑ Bandgap + ref Voltages + master I: switched ON/OFF
- ❑ Shut down bias currents with vdd always ON

SK2 power consumption measurement:

- ❑ 123 mA x 3.3V \approx 40 mW \Rightarrow 0.6 mW/ch
- ❑ 4 Power pulsing lines : analog, conversion, dac, digital
- ❑ Each chip can be forced on/off by slow control

Measurements

Acquisition	88 mA , 290 mW	Duty Cycle =0.5%, 1.45 mW
Conversion	27.3 mA, 90 mW	Duty Cycle =0.25%, 0.225 mW
Readout	8.0 mA, 26.4 mW	Duty Cycle =0.25%, 0.066 mW

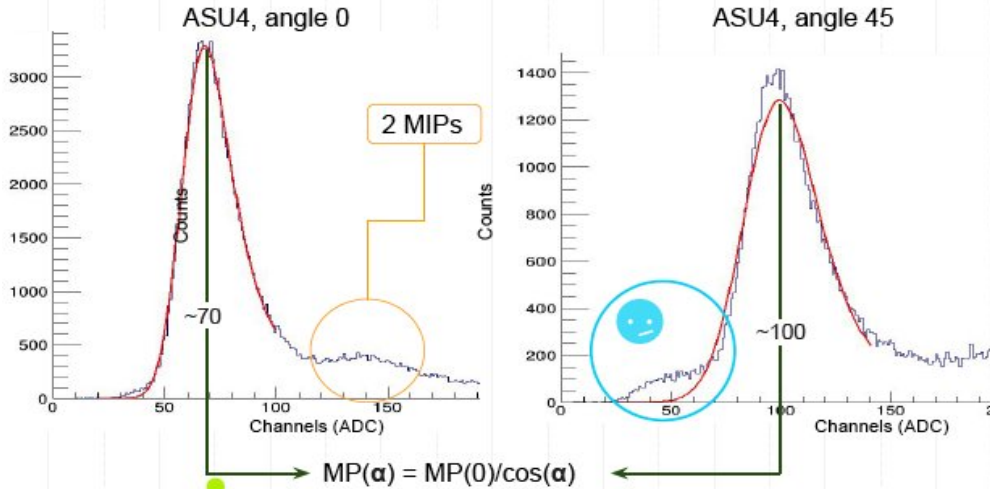
Skiroc2 power consumption with Power pulsing: 1.7 mW ie 27 $\mu\text{W}/\text{ch}$

Power estimations

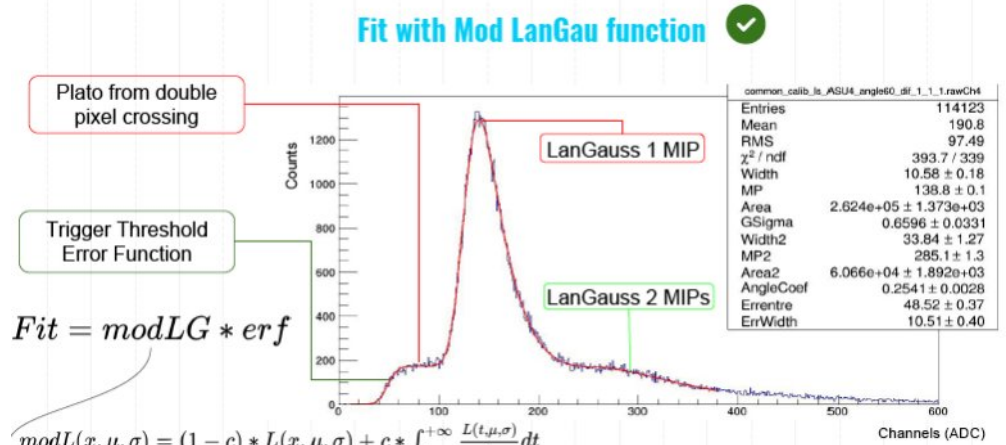
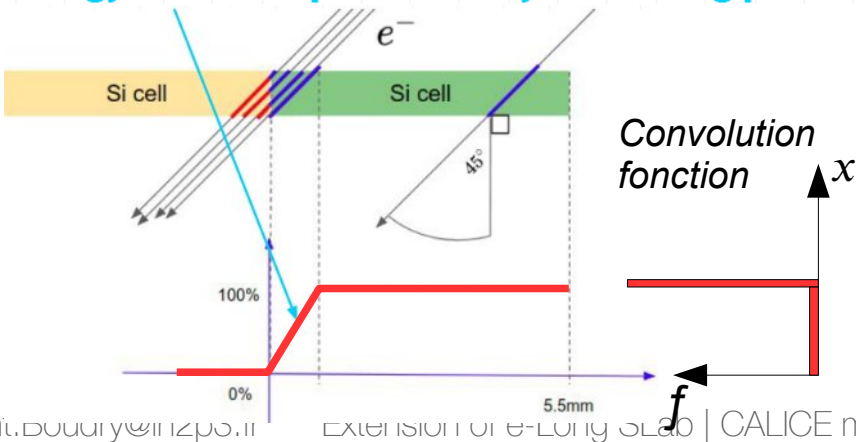
	mW
P_ACQ	290
P_CONV	90
P_RO	26

	TAU_PO/ms	E_PO/ μ J	Tau_SPILL/ms	E_ACQ/ μ J	tau_CONV/ms	E_CONV/ μ J	E_SPILL/ μ J	f_rep/Hz	P_TOT/ μ W	P_TOT/ μ W/chRatio	HL/Lumi
ILC	0,005	1,450	1,000	290,000	0,10	9	300,45	5	1502,25	23,47	
HL-ILC	0,005	1,450	2,000	580,000	0,20	18	599,45	15	8991,75	140,5	5,99
CLIC	0,005	1,450	0,176	51,040	0,02	1,58	54,07	50	2703,7	42,25	
HL-CLIC	0,005	1,450	0,176	51,040	0,02	1,58	54,07	100	5407,4	84,49	2

Mip analysis



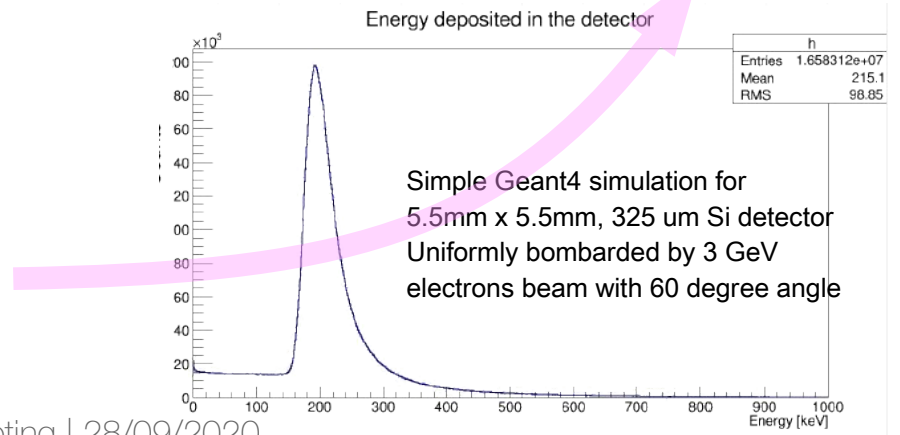
Pixel energy fraction depends linearly on crossing position



$Fit = modLG * erf$

$$modL(x, \mu, \sigma) = (1 - c) * L(x, \mu, \sigma) + c * \int_x^{+\infty} \frac{L(t, \mu, \sigma)}{t} dt$$

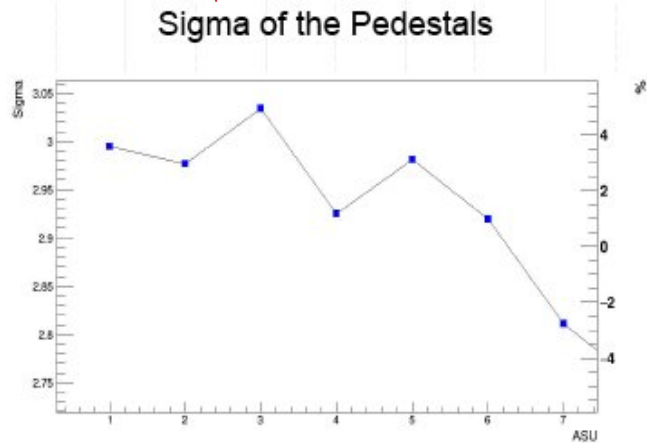
$$modLG = \int_{-\infty}^{+\infty} modL(t, \mu, \sigma) * G(x - t, \mu_G, \sigma_G) dt$$



MIP response vs position

mip MPV *cos(θ) vs ASU#

- OK for 4 1st ASU's
- Small drop ~of signal ~2%/ASU for \geq ASU#5
- Also hints similar drop on σ_{ped}



⇒ Voltage & Gain drop ?

Power pulsed mode with ballast et end of slab
(or just random build-up effect from chip variability ?)

